



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AON2411**

**12V P-Channel MOSFET**

### General Description

- Latest Trench Power MOSFET technology
- Very Low  $R_{DS(ON)}$  at 1.8V  $V_{GS}$
- Low Gate Charge
- ESD protection
- RoHS and Halogen-Free Compliant

### Application

- Battery path load switch
- System load switch

### Product Summary

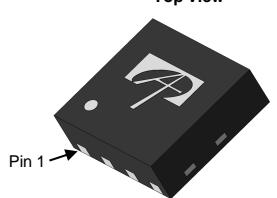
$V_{DS}$	-12V
$I_D$ (at $V_{GS}=-4.5V$ )	-20A
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 8mΩ
$R_{DS(ON)}$ (at $V_{GS}=-3.0V$ )	< 10.2mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$ )	< 11.6mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.8V$ )	< 17.5mΩ

### Typical ESD protection

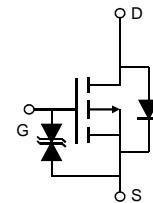
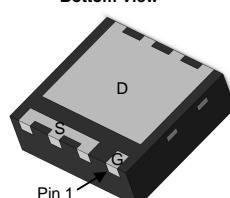
HBM Class 2



Top View DFN 2x2C



Bottom View



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AON2411	DFN 2x2C	Tape & Reel	3000

**Absolute Maximum Ratings  $T_A=25^\circ\text{C}$  unless otherwise noted**

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-12	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current <sup>A</sup> $T_A=25^\circ\text{C}$	$I_D$	-20	A
Current <sup>G</sup> $T_A=70^\circ\text{C}$		-15.5	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-80	
Power Dissipation <sup>B</sup> $T_A=25^\circ\text{C}$	$P_D$	5.0	W
$T_A=70^\circ\text{C}$		3.2	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10\text{s}$	$R_{0JA}$	20	25	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		45	55	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-12			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-12\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		-1	-5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.3	-0.6	-0.9	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-12\text{A}$ $T_J=125^\circ\text{C}$		6.6	8.0	$\text{m}\Omega$
		$V_{GS}=-3.0\text{V}, I_D=-11\text{A}$		8.6	10.4	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-10\text{A}$		9.2	11.6	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-8\text{A}$		13.7	17.5	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-12\text{A}$		60		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		-0.59	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-7	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-6\text{V}, f=1\text{MHz}$		2180		pF
$C_{oss}$	Output Capacitance			675		pF
$C_{rss}$	Reverse Transfer Capacitance			425		pF
$R_g$	Gate resistance	$f=1\text{MHz}$		13.5		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, I_D=-12\text{A}$		20	30	nC
$Q_{gs}$	Gate Source Charge			4		nC
$Q_{gd}$	Gate Drain Charge			5.5		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, R_L=0.5\Omega, R_{\text{GEN}}=3\Omega$		15		ns
$t_r$	Turn-On Rise Time			45		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			135		ns
$t_f$	Turn-Off Fall Time			185		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		28		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		13		nC

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{ C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{ C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

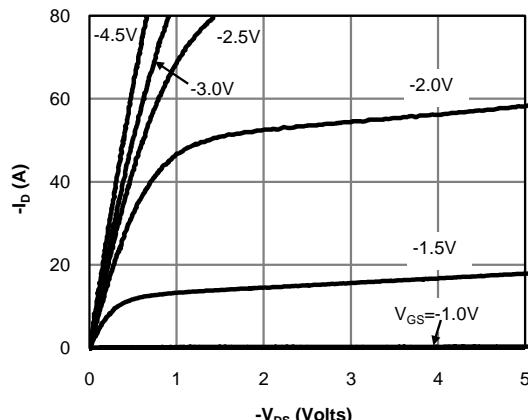
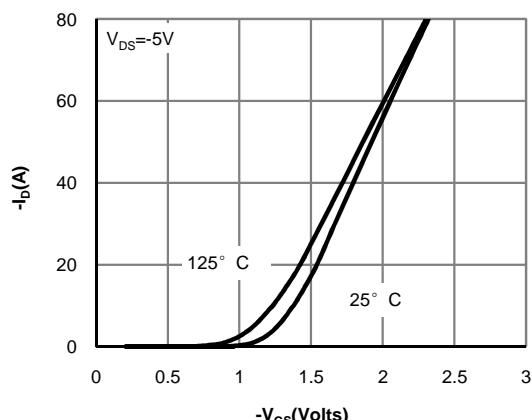
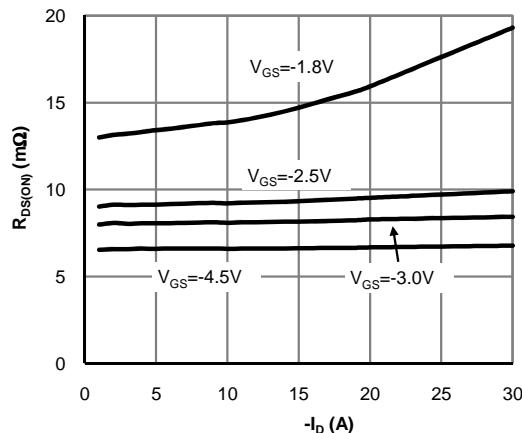
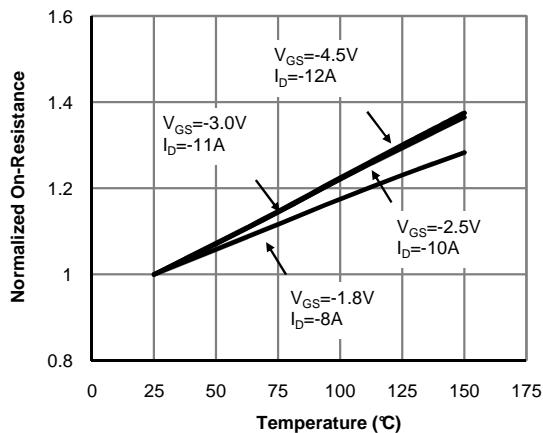
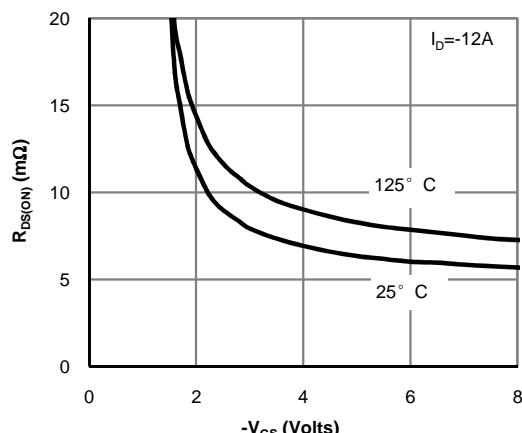
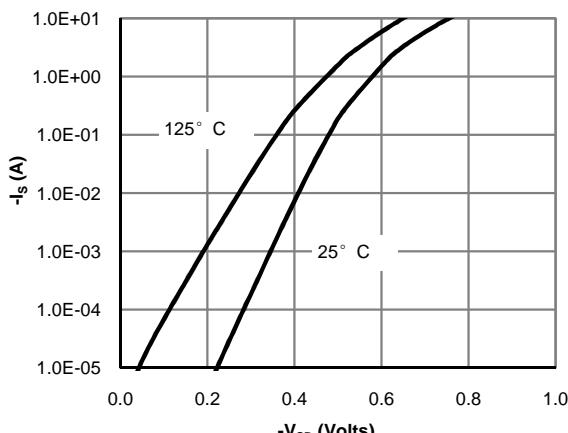
C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{ C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{ C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QUL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{ C}$ . The SOA curve provides a single pulse rating.

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

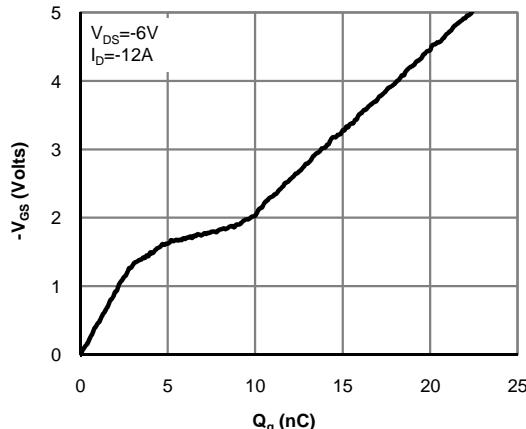
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge Characteristics

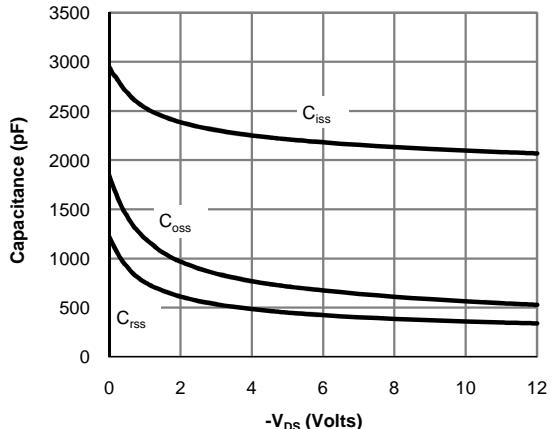


Figure 8: Capacitance Characteristics

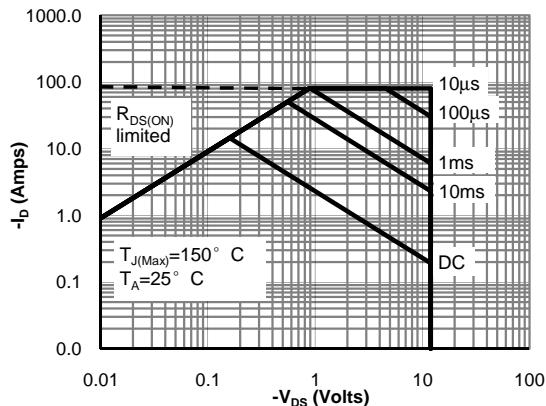


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

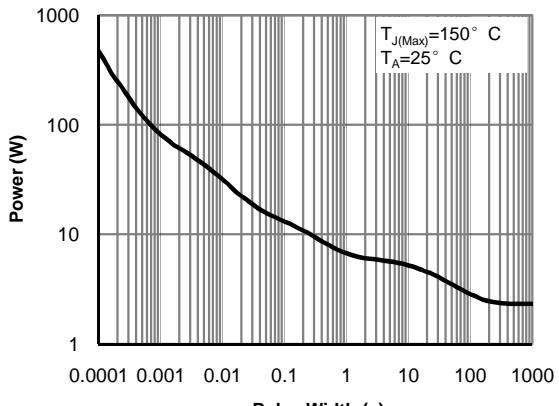
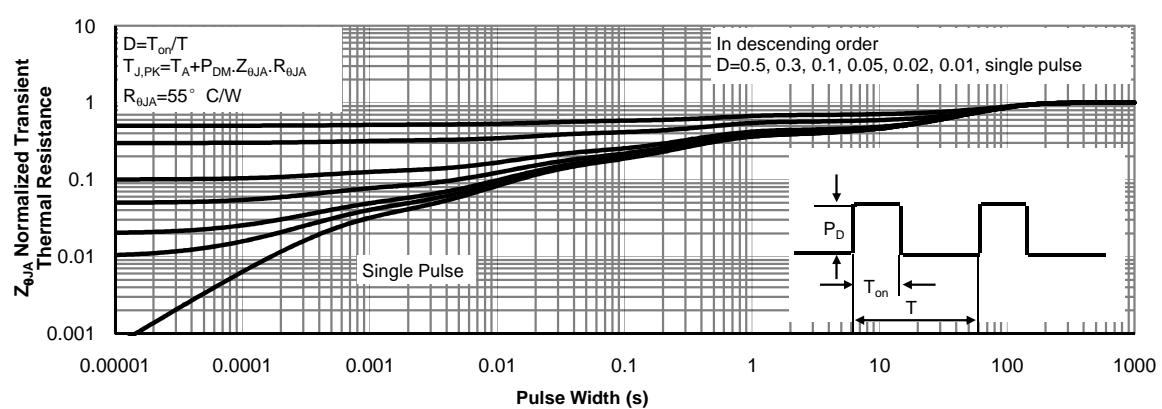
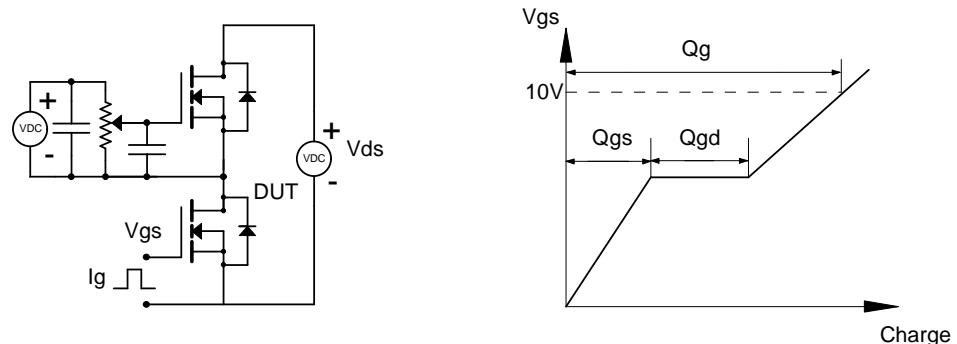
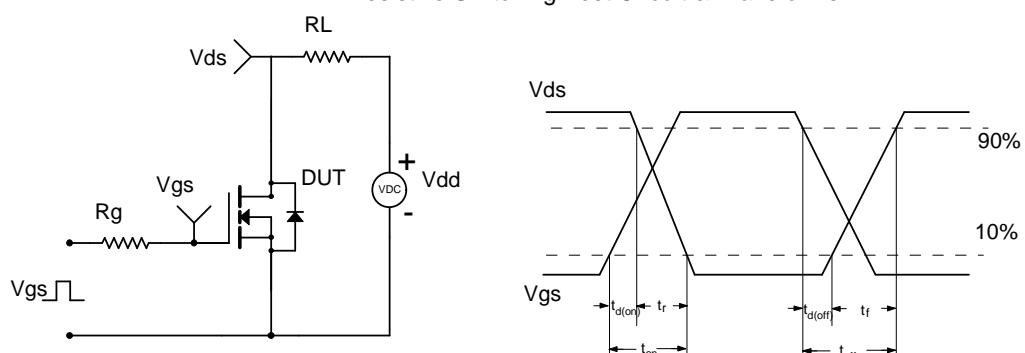
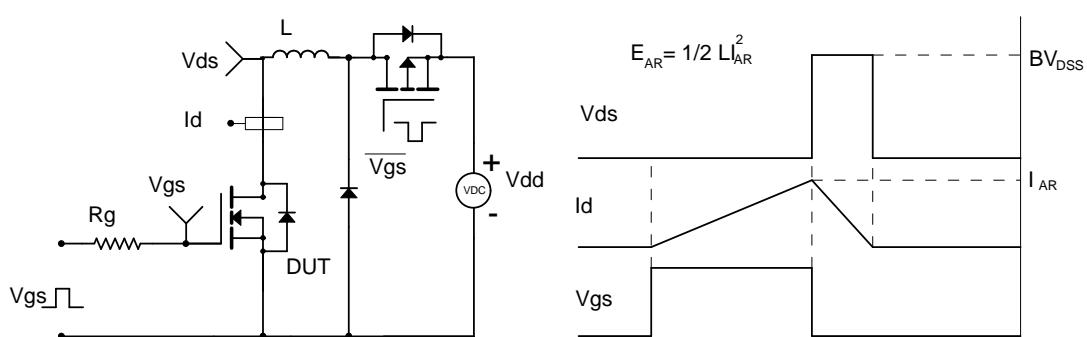


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)



**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
